

# Device Modeling Report

COMPONENTS: Silicon Carbide Schottky Diode  
PART NUMBER: CSD01060E  
MANUFACTURER: Cree, Inc.  
REMARK: Professional Model

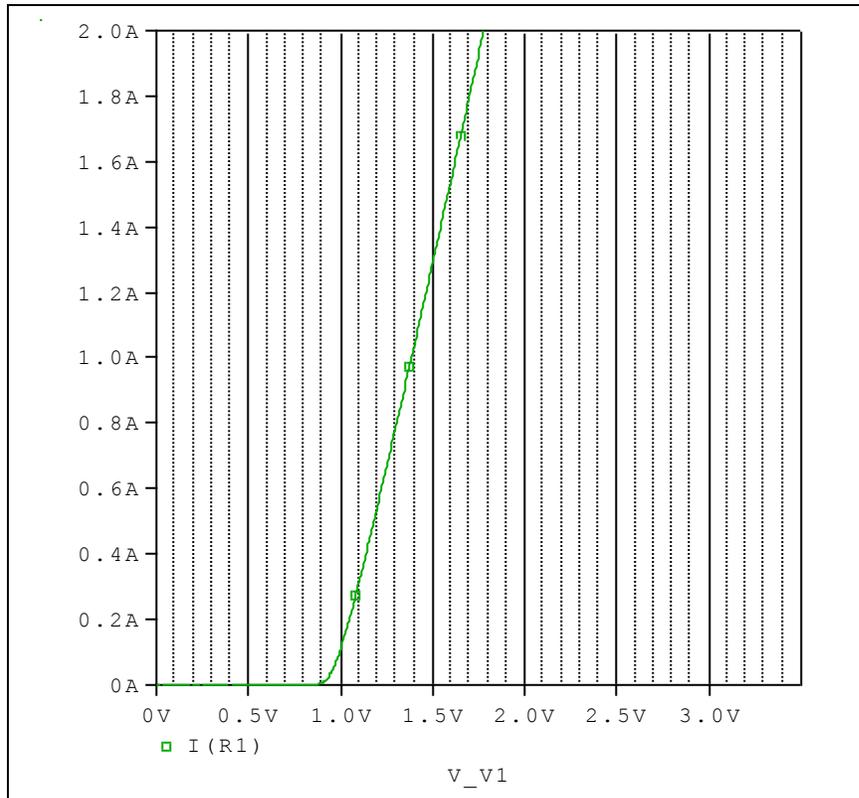


**Bee Technologies Inc.**

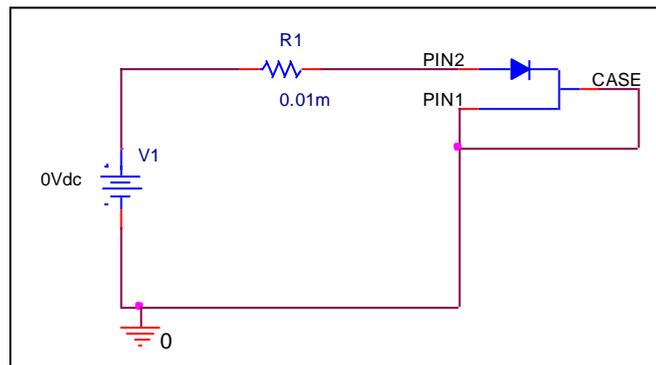
PSpice model parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time
EG	Energy-band Gap

# Forward Current Characteristic

## Circuit Simulation Result

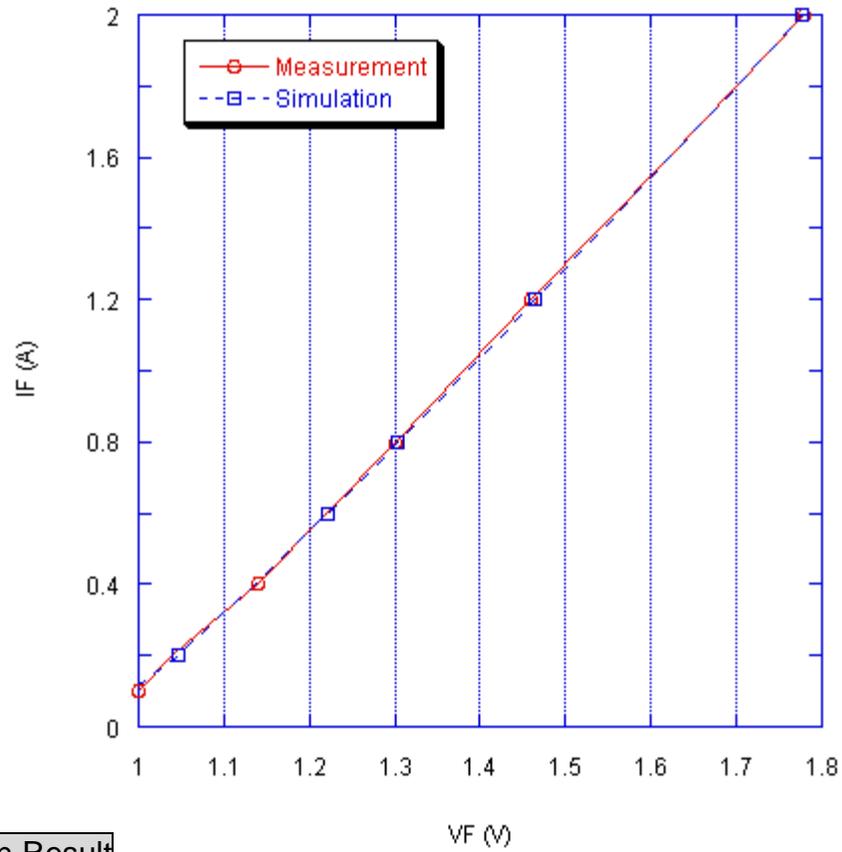


## Evaluation Circuit



# Comparison Graph

## Circuit Simulation Result

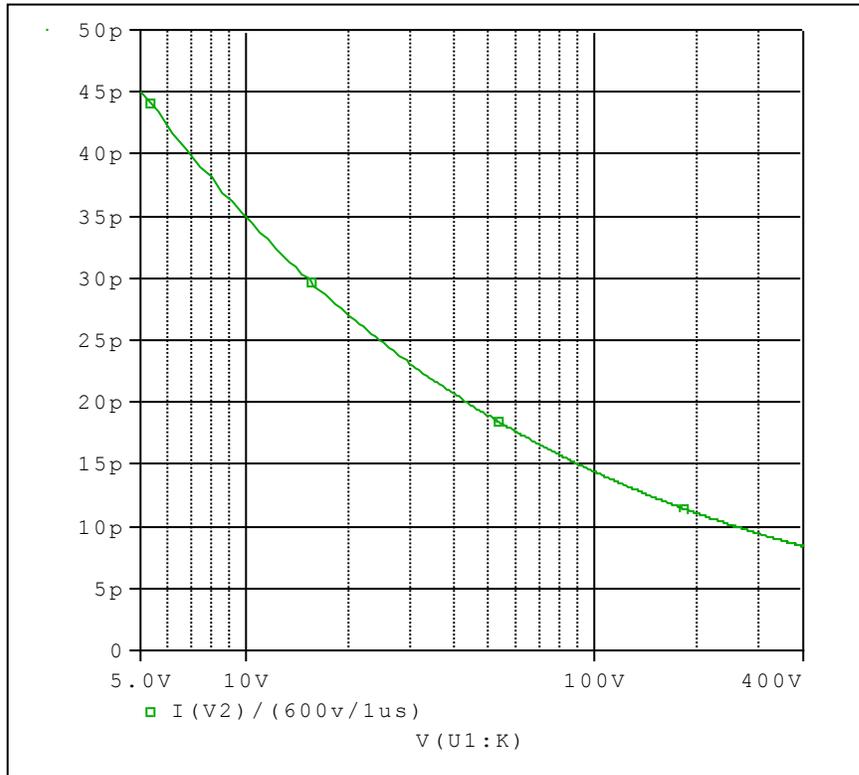


## Simulation Result

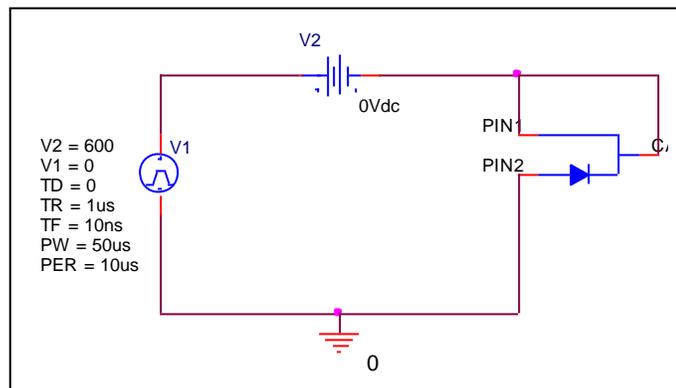
$I_F$ (A)	$V_F$ (V)		Error(%)
	Measurement	Simulation	
0.1	1.000	0.994	-0.604
0.2	1.040	1.047	0.669
0.4	1.140	1.138	-0.176
0.6	1.220	1.222	0.164
0.8	1.300	1.304	0.307
1	1.380	1.384	0.289
1.2	1.460	1.464	0.273
1.6	1.620	1.621	0.062
2	1.780	1.777	-0.169

# Junction Capacitance Characteristic

## Circuit Simulation Result

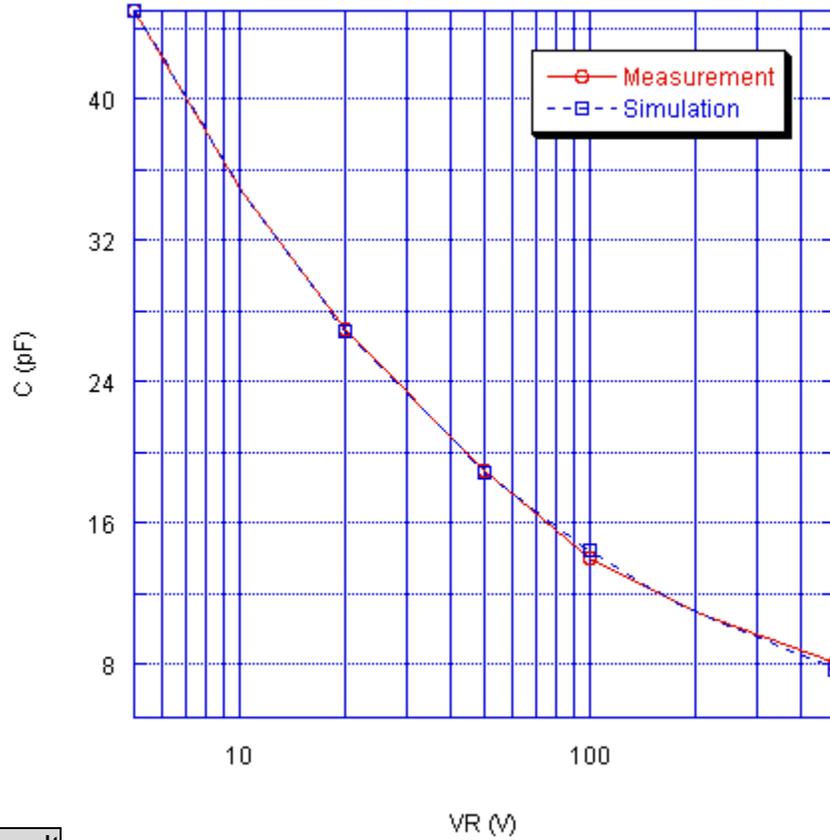


## Evaluation Circuit



# Comparison Graph

## Circuit Simulation Result

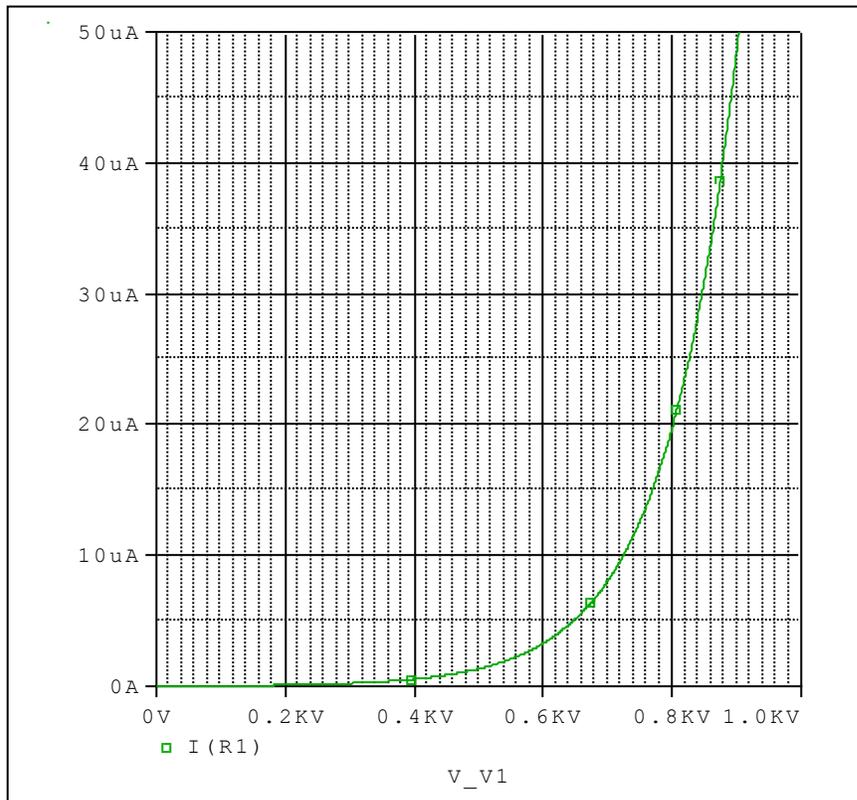


## Simulation Result

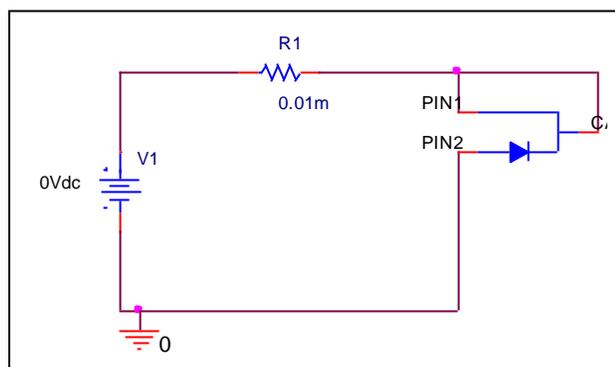
$V_R(V)$	$C_j(pF)$		Error(%)
	Measurement	Simulation	
5	45.000	44.965	-0.078
10	35.000	34.983	-0.049
20	27.000	26.917	-0.308
50	19.000	18.910	-0.476
100	14.000	14.423	2.933
200	11.000	10.994	-0.055
500	8.000	7.692	-4.004

# Reverse Characteristic

## Circuit Simulation Result

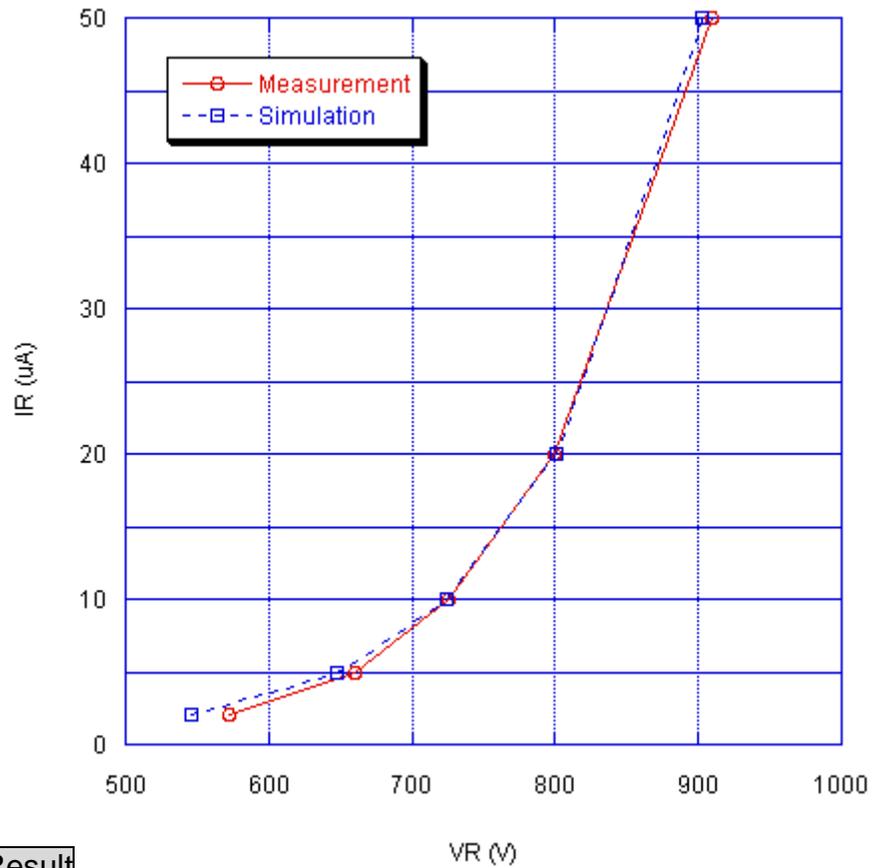


## Evaluation Circuit



## Comparison Graph

### Circuit Simulation Result



### Simulation Result

$I_R(\mu A)$	$V_R(V)$		Error(%)
	Measurement	Simulation	
2	573.000	545.307	-5.078
5	660.000	646.951	-2.017
10	725.000	724.015	-0.136
20	800.000	801.201	0.150
50	910.000	903.053	-0.769